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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/080,913	02/21/2002	Luu Thanh Nguyen	NSCIPI31X1	1176
	7590 10/29/2007		EXAMINER	
BEYER WEAV P.O. BOX 7025	50		EXAMINER ZARNEKE, DAVID A ART UNIT PAPER NUMBER	
OAKLAND, CA 94612-0250		•	ART UNIT	PAPER NUMBER
			2891	
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			10/29/2007	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

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i .	Application No.	Applicant(s)	
	10/080,913	NGUYEN ET AL.	
Office Action Summary	Examiner	Art Unit	-
	David A. Zarneke	2891	
The MAILING DATE of this communication a Period for Reply	ppears on the cover sheet wi	th the correspondence address	
A SHORTENED STATUTORY PERIOD FOR REF WHICHEVER IS LONGER, FROM THE MAILING - Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communication If NO period for reply is specified above, the maximum statutory perions for the provision of the period for reply within the set or extended period for reply will, by state that the period for reply will, by state that the period for the provision of t	DATE OF THIS COMMUNIO 1.136(a). In no event, however, may a rood will apply and will expire SIX (6) MON tute, cause the application to become AB	CATION. eply be timely filed THS from the mailing date of this communication. ANDONED (35 U.S.C. § 133).	
Status			
1) Responsive to communication(s) filed on <u>06</u>	September 2007.		
2a) This action is FINAL . 2b)⊠ TI	his action is non-final.		
3) Since this application is in condition for allow	vance except for formal matt	ers, prosecution as to the merits is	
closed in accordance with the practice unde	r <i>Ex parte Quayle</i> , 1935 C.D	. 11, 453 O.G. 213.	
Disposition of Claims			
4) Claim(s) 19-43 is/are pending in the applicate 4a) Of the above claim(s) is/are withd 5) Claim(s) is/are allowed. 6) Claim(s) 19-43 is/are rejected. 7) Claim(s) is/are objected to. 8) Claim(s) are subject to restriction and are subject to restriction and are subject to restriction and are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on is/are: a) are subjected to by the Examination The drawing(s) filed on	rawn from consideration. d/or election requirement. iner. ccepted or b) objected to he drawing(s) be held in abeyar ection is required if the drawing	ce. See 37 CFR 1.85(a). (s) is objected to. See 37 CFR 1.121(d).	
11) ☐ The oath or declaration is objected to by the	Examiner. Note the attached	Office Action or form PTO-152.	
Priority under 35 U.S.C. § 119			
12) Acknowledgment is made of a claim for forei a) All b) Some * c) None of: 1. Certified copies of the priority docume 2. Certified copies of the priority docume 3. Copies of the certified copies of the priority docume application from the International Bure * See the attached detailed Office action for a li	ents have been received. ents have been received in A riority documents have been eau (PCT Rule 17.2(a)).	pplication No received in this National Stage	
Attachment(s)			
 Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date 	Paper No(iummary (PTO-413) s)/Mail Date nformal Patent Application 	

Art Unit: 2891

DETAILED ACTION

Response to Arguments

Applicant's arguments, filed 9/6/07, with respect to the rejection of claims have been fully considered and are persuasive. Therefore, the rejection has been withdrawn. However, upon further consideration, a new ground(s) of rejection is made below.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Claims 19, 20-22, 24-27, 33, and 34 rejected under 35 U.S.C. 102(e) as being clearly anticipated by Capote et al., US Patent Application Publication 2002/0014703.

Capote (figures 3, 5-8) teaches an apparatus, comprising:

a flip chip integrated circuit [10] having flip chip bond pads [24] with solder bumps [30] formed directly on an active surface of the flip chip; and

a substantially uniform layer of partially cured reflowable underfill adhesive [22] applied directly on the active surface of the flip chip integrated circuit and around the solder bumps formed onto the active surface, the substantially uniform layer of underfill

Art Unit: 2891

[0040]).

adhesive and the flip chip integrated circuit together forming continuous cut edges around the periphery of the flip chip (figures 3, 5-8 clearly show a continuous cut edges around the periphery of the flip chip), the partially cured reflowable underfill adhesive having properties suitable for reflowing during solder reflow of the solder bumps at a solder reflow temperature when the flip chip is being mounted onto a substrate so that the reflowable underfill material substantially fills the gap between the flip chip and the

substrate and further cures in the gap between the flip chip and the substrate (4, 2+ &

While note specifically stating that the underfill adhesive is partially cured, the material [22] must have been partially hardened because the only way one can form the openings [28] in figure 6 is to an at least hardened material. Meaning that one can't form openings in a liquid.

Regarding claim 20, Capote teaches the underfill adhesive includes one or more of the following components: an epoxy resin, a hardener, a catalyst initiator, a coloring dye, and an inorganic filler ([0055] & [0056]).

Regarding claim 21, Capote teaches the underfill adhesive has a coefficient of thermal expansion substantially similar to that of the substrate upon which the flip chip integrated circuit is intended to be mounted [0023].

With respect to claim 22, Capote teaches the underfill adhesive is deposited on the active surface of the flip chip integrated circuit at a pre-cured height such that the solder bumps are at least exposed through the underfill adhesive after curing (figure 7).

Art Unit: 2891

With respect to claim 24, Capote teaches the underfill adhesive layer is deposited on the active surface of the flip chip integrated circuit in wafer form before the flip chip integrated circuit is singulated from the wafer [0025].

As to claim 25, Capote teaches the underfill adhesive is selected from the group comprising: epoxies, poly-imides [0037], silicone-polyimide copolymers.

In re claim 26, Capote teaches the substrate has a plurality of contact pads, the contact pads configured to contact the solder bumps of the flip chip when the flip chip is mounted onto the substrate, the contact pads and the solder bumps forming joints electrically connecting the flip chip to the substrate (figure 3).

Regarding claim 27, Capote teaches the underfill adhesive material is in one of the following states, either fully cured or partially cured.

With respect to claim 33, Capote teaches a solder paste (4, 1+) is provided on the contact pads of the substrate.

As to claim 34, Capote teaches a fluxing material is provided on the substrate [0057].

Claims 35, 36, and 38 rejected under 35 U.S.C. 102(e) as being clearly anticipated by Capote et al., US Patent Application Publication 2002/0014703.

Capote teaches an apparatus, comprising:

a semiconductor wafer [0025] having an active surface including a plurality of die formed thereon;

one or more bond pads [24] formed on the plurality of die;

one or more solder bumps [30] formed on the one or more bond pads respectively; and

a layer of at least partially cured reflowable underfill adhesive (22) formed around the solder bumps on the active surface of the wafer, the reflowable underfill adhesive having properties suitable for reflowing during solder reflow of the solder bumps at a solder reflow temperature when the individual die are being mounted onto a substrate so that the reflowable underfill material substantially fills the gap between the individual die and the substrate and further cures in the gap between the flip chip and the substrate (4, 2+ & [0040].

Regarding claim 36, Capote teaches the underfill adhesive is deposited on the active surface of the wafer at a pre-cured height such that the solder bumps are at least exposed through the underfill adhesive after the partial curing (figure 7).

With respect to claim 38, Capote teaches the underfill adhesive is selected from the group comprising: epoxies, poly-imides [0037], silicone-polyimide copolymers.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Art Unit: 2891

The factual inquiries set forth in *Graham* v. *John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

- 1. Determining the scope and contents of the prior art.
- 2. Ascertaining the differences between the prior art and the claims at issue.
- 3. Resolving the level of ordinary skill in the pertinent art.
- 4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

Claims 23, 28-32, 37, and 39-42 are rejected under 35 U.S.C. 103(a) as being unpatentable over Capote et al., US Patent Application Publication 2002/0014703, as applied to claims 19 and 35 above respectively.

Regarding claim 23 and 37, while Capote fails to teach the pre-cured height of the underfill adhesive applied to the wafer ranges from 140% to 90% of the height of the solder bumps, it would have been obvious to one ordinary skill in the art at the time of the invention to optimize the pre-cured height of the underfill adhesive through routine experimentation (MPEP 2144.05).

With respect to claims 28 and 39, while Capote fails to teach the layer of underfill adhesive is substantially opaque thereby protecting the flip chip integrated circuit from photo induced leakage currents by blocking visible light, it would have been obvious to one ordinary skill in the art at the time of the invention to optimize the opacity of the underfill adhesive through routine experimentation (MPEP 2144.05).

As to claims 29 and 40, while Capote fails to teach the underfill adhesive has a coefficient of thermal expansion in the range of approximately 20 x 10-6/K to approximately 30 x 10-6/K @ 25 °C, it would have been obvious to one ordinary skill in

the art at the time of the invention to optimize the coefficient of thermal expansion of the underfill adhesive through routine experimentation (MPEP 2144.05).

In re claims 30 and 41, while Capote fails to teach the underfill adhesive melts at between 120 to 140 degrees C and reacts at between 175 to 195 degrees C, it would have been obvious to one ordinary skill in the art at the time of the invention to optimize the melt and reaction temperatures of the underfill adhesive through routine experimentation (MPEP 2144.05).

Regarding claims 31 and 42, while Capote fails to teach the underfill adhesive has an elastic modulus in the range of 1 to 10 GPa, it would have been obvious to one ordinary skill in the art at the time of the invention to optimize the elastic modulus of the underfill adhesive through routine experimentation (MPEP 2144.05).

With respect to claims 32 and 43, while Capote fails to teach a dam around the periphery of the wafer to prevent the underfill material deposited onto the surface of the wafer from flowing off the wafer before the partial curing of the adhesive layer, the use of a dam is conventionally known in the art to skilled artisans to prevent the flowing of the underfill adhesive. The use of conventional materials to perform their known functions is obvious (MPEP 2144.07).

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to David A. Zarneke whose telephone number is (571)-272-1937. The examiner can normally be reached on M-Th 7:30 AM-6 PM.

Art Unit: 2891

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, William Baumeister can be reached on (571)-272-1722. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Page 8

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/David A. Zarneke/ Primary Examiner October 13, 2007